

PROBLEM ADVISORY

1. TITLE NOTIFICATION OF MISSING PIN LEAKAGE TEST OF MICROCIRCUIT, MEMORY, DIGITAL, CMOS, (1,2,4)MEG X 32-BIT , RADIATION-HARDENED, DUAL VOLTAGE SRAM with embedded EDAC, MULTICHIP MODULE			2. DOCUMENT NUMBER SPO-2022-PA-0002	
			3. DATE (Year, Month, Date) 2022/07/28	
4. MANUFACTURER NAME AND ADDRESS CAES 4350 CENTENNIAL BOULEVARD COLORADO SPRINGS, COLORADO 80907-3486			5. MANUFACTURER POINT OF CONTACT NAME Peter Nelson	
			6. MANUFACTURER POINT OF CONTACT TELEPHONE 719-594-8000	
			7. MANUFACTURER POINT OF CONTACT EMAIL Peter.b.nelson@caes.com	
8. CAGE CODE 65342	9. LDC START All	10. LDC END All	11. PRODUCT IDENTIFICATION CODE QS10, QS12, QS17	12. BASE PART UT8ERxM32S
13. BLANK			14. SMD NUMBER 10202, 10203, 10204	15. DEVICE TYPE DESIGNATOR 02, 04, 06, 08
			16. RHA LEVELS All	17. QML LEVEL All
			18. NON QML LEVEL All	19. GIDEP NUMBER GB4-C-22-0006

20. PROBLEM DESCRIPTION / DISCUSSION / EFFECT

During a test program review, it was discovered that input leakage was not measured on input pin /Scrub for all slave stacked SRAMs. This issue covers only slave devices and not master devices. No devices have failed at the customer and is considered a low risk.

Affected PN	PIC#	Assembly Lot ID	Date Code
5962R1020202QXC	QS17	All	All
5962L1020202QXC	QS17	All	All
5962R1020202VXC	QS17	All	All
5962L1020202VXC	QS17	All	All
5962R1020204QXC	QS17	All	All
5962L1020204QXC	QS17	All	All
5962R1020206QXC	QS17	All	All
5962L1020206QXC	QS17	All	All
5962R1020206VXC	QS17	All	All
5962L1020206VXC	QS17	All	All
5962R1020302QXC	QS10	All	All
5962L1020302QXC	QS10	All	All

20. PROBLEM DESCRIPTION / DISCUSSION / EFFECT (Cont'd)

Affected PN	PIC#	Assembly Lot ID	Date Code
5962R1020302VXC	QS10	All	All
5962L1020302VXC	QS10	All	All
5962R1020304QXC	QS10	All	All
5962L1020304QXC	QS10	All	All
5962R1020402QXC	QS12	All	All
5962L1020402QXC	QS12	All	All
5962R1020404QXC	QS12	All	All
5962L1020404QXC	QS12	All	All
5962R1020406QXC	QS12	All	All
5962L1020406QXC	QS12	All	All
5962R1020408QXC	QS12	All	All
5962L1020408QXC	QS12	All	All
UT8ER1M32S-21X*	QS17	All	All
UT8ER2M32S-22X*	QS10	All	All
UT8ER4M32S-25X*	QS12	All	All

21. ACTION TAKEN / PLANNED

The test programs for each part are being updated to include an input leakage test for the /Scrub pin.

22. DISPOSITIONARY RECOMMENDATION:

CHECK &
USE AS IS

CONTACT
MANUFACTURER

REMOVE &
REPLACE

CORRECT &
USE AS SPECIFIED